



# **Phase Control Thyristor**

# **Preliminary Information**

DS5894-1.1 August 2007 (LN25569)

#### **FEATURES**

- Double Side Cooling
- High Surge Capability

### **APPLICATIONS**

- High Power Drives
- High Voltage Power Supplies
- Static Switches

#### **VOLTAGE RATINGS**

Part and Ordering Number	Repetitive Peak Voltages V <sub>DRM</sub> and V <sub>RRM</sub> V	Conditions
DCR470G85 DCR470G80 DCR470G70	8500 8000 7000	$\begin{split} T_{vj} &= \text{-}40^\circ\!\text{C to }125^\circ\!\text{C},\\ I_{DRM} &= I_{RRM} = 100\text{mA},\\ V_{DRM}, V_{RRM}t_p &= 10\text{ms},\\ V_{DSM}\&V_{RSM} &= \\ V_{DRM}\&V_{RRM} + 100V\\ respectively \end{split}$

Lower voltage grades available.

# **KEY PARAMETERS**

$V_{DRM}$	8500V
$I_{T(AV)}$	467A
I <sub>TSM</sub>	5250A
dV/dt*	1500V/μs
dl/dt	200A/us

### \* Higher dV/dt selections available

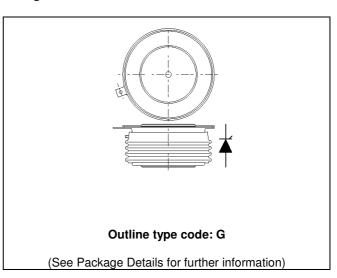


Fig. 1 Package outline

#### **ORDERING INFORMATION**

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

#### DCR470G85

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.



## **CURRENT RATINGS**

## $T_{\text{case}}$ = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Si	de Cooled			
I <sub>T(AV)</sub>	Mean on-state current	Half wave resistive load	467	Α
I <sub>T(RMS)</sub>	RMS value	-	734	Α
I <sub>T</sub>	Continuous (direct) on-state current	-	725	Α

## **SURGE RATINGS**

Symbol	Parameter	Test Conditions	Max.	Units
I <sub>TSM</sub>	Surge (non-repetitive) on-state current	10ms half sine, T <sub>case</sub> = 125℃	5.25	kA
l <sup>2</sup> t	I <sup>2</sup> t for fusing	$V_R = 0$	0.138	MA <sup>2</sup> s

## THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance – junction to case	Double side cooled	DC	-	0.0268	.c/M
		Single side cooled	Anode DC	-	0.0527	.c/M
			Cathode DC	-	0.0652	.c/M
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink	Clamping force 11.5kN	Double side	-	0.0072	.c/M
		(with mounting compound)	Single side	-	.0144	.c/M
T <sub>vj</sub>	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T <sub>stg</sub>	Storage temperature range			-55	125	°C
Fm	Clamping force			10	13	kN





# **DYNAMIC CHARACTERISTICS**

Symbol	Parameter	Test Conditio	Test Conditions		Max.	Units
I <sub>RRM</sub> /I <sub>DRM</sub>	Peak reverse and off-state current	At V <sub>RRM</sub> /V <sub>DRM</sub> , T <sub>case</sub> = 125 ℃		-	100	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V <sub>DRM</sub> , T <sub>j</sub> = 125℃, ga	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V <sub>DRM</sub> to 2x I <sub>T(AV)</sub>	Repetitive 50Hz	-	100	A/μs
		Gate source 30V, 10Ω,	Non-repetitive	-	200	A/μs
		$t_r < 0.5 \mu s, T_j = 125 {}^{\circ}\!C$				
$V_{T(TO)}$	Threshold voltage – Low level	50A to 400A at T <sub>case</sub> = 125 ℃	;	-	1.162	٧
	Threshold voltage – High level	400A to 1600A at T <sub>case</sub> = 125	5℃	-	1.3063	V
r <sub>T</sub>	On-state slope resistance – Low level	50A to 400A at T <sub>case</sub> = 125 ℃	;	-	3.153	mΩ
	On-state slope resistance – High level	400A to 1600A at T <sub>case</sub> = 125 ℃		-	2.763	mΩ
t <sub>gd</sub>	Delay time	$V_D = 67\% V_{DRM}$ , gate source	30V, 10Ω	TBD	TBD	μs
		t <sub>r</sub> = 0.5μs, T <sub>j</sub> = 25℃				
tq	Turn-off time	$T_j = 125 ^{\circ}\text{C}, V_R = 200 ^{\circ}\text{V}, dI/dt$	= 5A/μs,	1000	1600	μs
		dV <sub>DR</sub> /dt = 20V/μs linear				
Qs	Stored charge	$I_T = 500A$ , $T_j = 125$ °C, $dI/dt = 5A/\mu s$ ,		2000	2600	μC
IL	Latching current	$T_j = 25$ °C, $V_D = 5$ V		-	3	А
lн	Holding current	$T_j = 25 {}^{\circ}\text{C},  R_{G-K} = \infty,  I_{TM} = 50$	0A, I <sub>T</sub> = 5A	-	300	mA



#### **GATE TRIGGER CHARACTERISTICS AND RATINGS**

Symbol	Parameter	Test Conditions	Max.	Units
$V_{GT}$	Gate trigger voltage	V <sub>DRM</sub> = 5V, T <sub>case</sub> = 25 ℃	1.5	V
$V_{GD}$	Gate non-trigger voltage	At V <sub>DRM</sub> , T <sub>case</sub> = 125 °C	TBD	V
I <sub>GT</sub>	Gate trigger current	V <sub>DRM</sub> = 5V, T <sub>case</sub> = 25 ℃	250	mA
I <sub>GD</sub>	Gate non-trigger current	V <sub>DRM</sub> = 5V, T <sub>case</sub> = 25 ℃	TBD	mA

#### **CURVES**

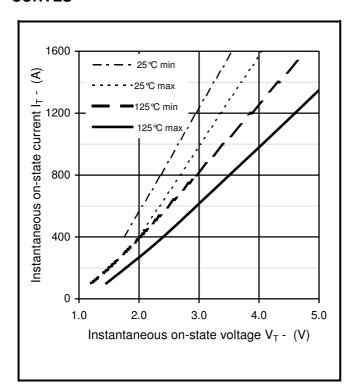
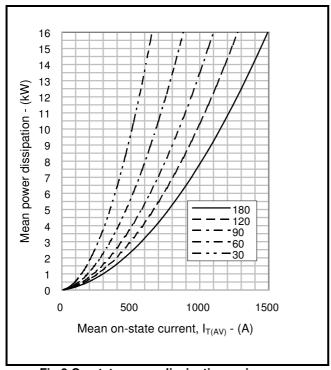
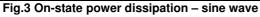


Fig.2 Maximum & minimum on-state characteristics

these values are valid for  $T_j = 125$  °C for  $I_T$  50A to 1600A







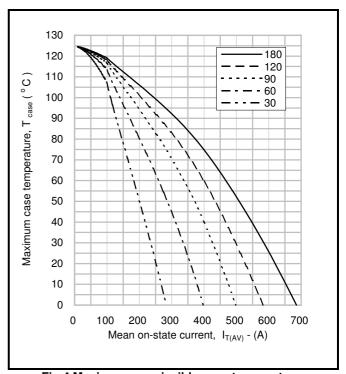


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

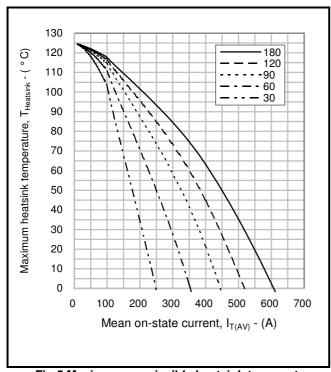


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

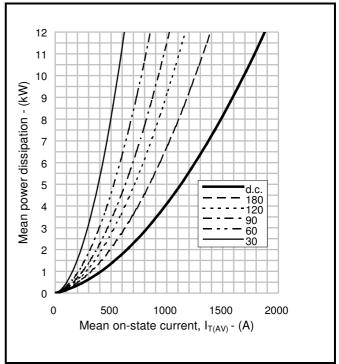


Fig.6 On-state power dissipation - rectangular wave



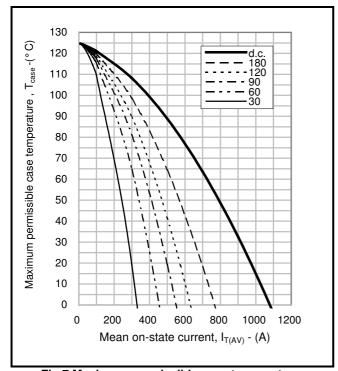


Fig.7 Maximum permissible case temperature, double side cooled – rectangular wave

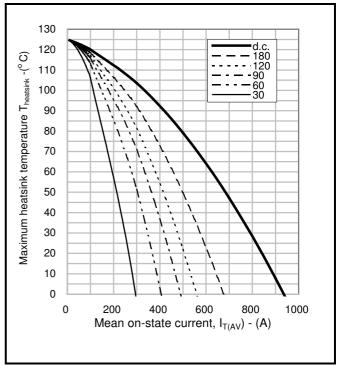
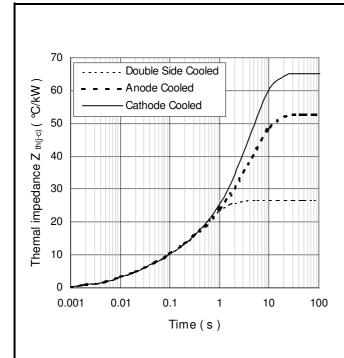


Fig.8 Maximum permissible heatsink temperature, double side cooled – rectangular wave



		1	2	3	4
Double side cooled	R <sub>i</sub> (°C/kW)	2.2995	5.4226	16.9074	2.1488
	T <sub>i</sub> (s)	0.0066401	0.0457025	0.4962482	1.8248
Anode side cooled	R <sub>i</sub> (℃/kW)	2.3214	5.2661	10.2686	34.8031
	T <sub>i</sub> (s)	0.0066948	0.045528	0.3484209	4.582
Cathode side cooled	R <sub>i</sub> (℃/kW)	2.4895	5.9105	7.4256	49.3432
	T; (s)	0.0070404	0.052895	U 38338U3	4 2295

 $Z_{th} = \sum [R_i \times (1-exp. (t/t_i))]$  [1]

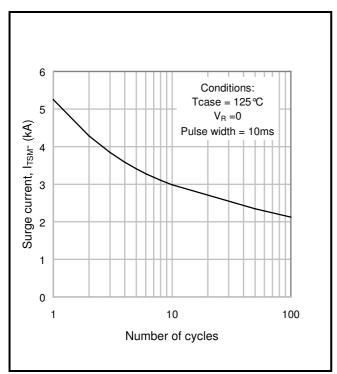
 $\Delta \, \text{R}_{\text{th(j-c)}}$  Conduction

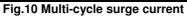
Tables show the increments of thermal resistance  $R_{\text{th}(j\text{-}c)}$  when the device operates at conduction angles other than d.c.

Double side cooling				Anode Side Cooling			
	$\Delta Z_{th}(z)$				$\Delta Z_t$	h (Z)	
θ°	sine.	rect.		θ°	sine.	rect.	
180	4.15	2.72		180	4.15	2.72	
120	4.90	4.02		120	4.89	4.02	
90	5.74	4.79		90	5.73	4.78	
60	6.53	5.65		60	6.52	5.65	
30	7.16	6.64		30	7.15	6.62	
15	7 46	7 18	Ī	15	7 44	7 16	

Ca	Cathode Sided Cooling			
	$\Delta Z_{th}(z)$			
θ°	sine.	rect.		
180	4.13	2.71		
120	4.87	4.00		
90	5.69	4.76		
60	6.46	5.60		
30	7.07	6.56		

Fig.9 Maximum (limit) transient thermal impedance – junction to case (°C/kW)





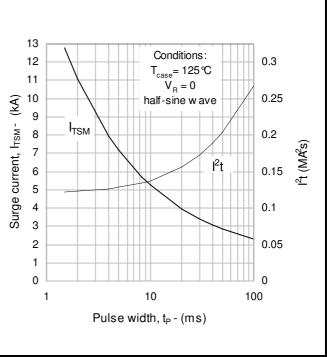


Fig.11 Single-cycle surge current

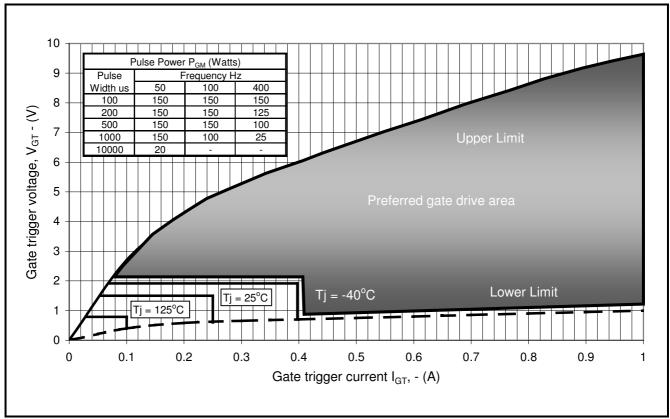


Fig12 Gate Characteristics

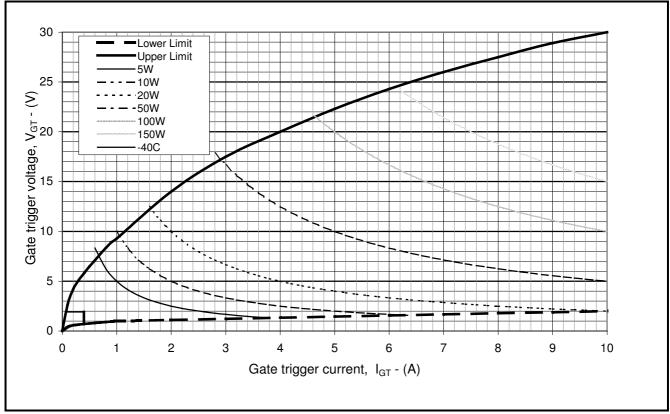


Fig. 13 Gate characteristics



#### **PACKAGE DETAILS**

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

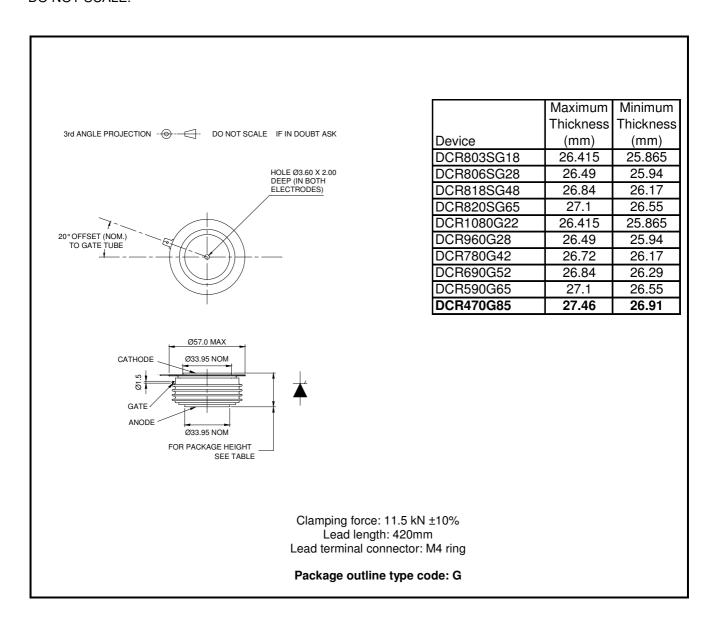


Fig.14 Package outline





#### **POWER ASSEMBLY CAPABILITY**

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

#### **HEATSINKS**

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



http://www.dynexsemi.com

e-mail: power solutions@dynexsemi.com

HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD

Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom.

Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 **CUSTOMER SERVICE** 

Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

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